X-Ray Photoelectron Spectroscopy (XPS)

Technical Parameters

Photoelectron Spectrometer:
PHI VersaProbe II

X-Ray Source: Aluminium anode (Al Kα, photon energy 1486,6 eV)
Ion Source: Ar^+ Ions (Energy 0.25-5 keV)
Primary Beam: mono chromatised AlKα - 1486,6 eV

Signal Detected: Photoelectrons
Elements Detected: Li – U Chemical bonding information
Lateral Resolution: 10 µm – 100 µm
Depth Resolution: 2 - 5 nm (Profiling Mode)
Detection Limit: 0.5 at%

Application areas

- Surface analysis of organic and inorganic materials
- Determining composition and chemical state information from surfaces
- Depth profiling for thin film composition
- Thin film oxide thickness measurements

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